



SLOVENSKI STANDARD
SIST EN 123100:2002/A1:2002
01-junij-2002

Amendment to table IV of EN

Sectional Specification: Single and double-sided printed boards with plain holes

Rahmenspezifikation: Leiterplatten mit Leiterbildern auf einer oder auf beiden Seiten ohne metallisierte Löcher

Spécification intermédiaire: Cartes imprimées simples et doubles faces à trous non métallisés

STANDARD PREVIEW
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Ta slovenski standard je istoveten z: EN 123100:1992/A1:1995

SIST EN 123100:2002/A1:2002
<https://standards.iteh.ai/catalog/standards/sist/en/123100-410c-483c-9575-4741ace8af5e/sist-en-123100-2002-a1-2002>

ICS:

31.180 Vě \ a ě ^: lē \ Q Dē Ā \ a ě ^ Printed circuits and boards
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EUROPEAN STANDARD
NORME EUROPÉENNE
EUROPÄISCHE NORM

EN 123100/A1

August 1995

ICS 31.180

Descriptors: Printed boards, single and double sided, plain holes, test specimens, capability test, quality conformance inspection, test patterns

English version

**Sectional Specification:
Single and double sided printed boards with plain holes**

Spécification intermédiaire:
Cartes imprimées simples et doubles
faces à trous non métallisés

Rahmenspezifikation:
Leiterplatten mit Leiterbildern auf einer
oder auf beiden Seiten ohne
metallisierte Löcher

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REPUBLIKA SLOVENIJA
MINISTRSTVO ZA ZNANOST IN TEHNOLOGIJO
Urad RS za standardizacijo in meroslovje
LJUBLJANA

<https://standards.iTeh.ai/catalog/standards/sist-en-123100-a1-2002>

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SIST. EN 123100/A1

PREVZET PO METODI RAZGLASITVE

-00- 1997

This amendment A1 modifies the European Standard EN 123100:1992; it was approved by CENELEC on 1995-07-04. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this amendment the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This amendment exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Denmark, Finland, France, Germany, Greece, Iceland, Ireland, Italy, Luxembourg, Netherlands, Norway, Portugal, Spain, Sweden, Switzerland and United Kingdom.

CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: rue de Stassart 35, B - 1050 Brussels

Foreword

This amendment was prepared by CLC/TC CECC/WG 23.

The text of the draft was submitted to the Unique Acceptance Procedure and was approved by CENELEC as amendment A1 to EN 123100:1992 on 1995-07-04.

The following dates were fixed:

- latest date by which the amendment has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 1996-07-01
- latest date by which the national standards conflicting with the amendment have to be withdrawn (dow) 1996-07-01

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[SIST EN 123100:2002/A1:2002](https://standards.iteh.ai/catalog/standards/sist/cfd10cd0-410e-483c-9373-4741acc8af5c/sist-en-123100-2002-a1-2002)

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Amendment A1 to EN 123100:1992

Introduce the data on pages 3, 4 and 5 of this amendment into table IV of EN 123100.

NOTE: The asterisk denotes a changed or new characteristic.

Table IV

Inspection Group	Characteristic	Test No	Level A		Level C	
			IL	AQL	IL	AQL
Group A						
Sub-Group A1						
	<u>Visual Inspection</u>					
	Conformity	1	S2	2.5%	100%	
	Identification	1a	S2	2.5%	100%	
	Appearance	1a	S2	2.5%	100%	
	Workmanship	1a	S2	2.5%	100%	
	* Conductor Defects	1a	S2	2.5%	100%	
	* Misalignment of Solder Resist and Land	1a	S2	2.5%	100%	
	Particles between conductors	1b, 1c	S2 S2	2.5% 2.5%	100% 100%	
Sub-Group A2						
	<u>Dimensional Examination</u>					
	Board Dimensions	2	S1	4.0%	S4	2.5%
	Holes	2	S1	4.0%	S4	2.5%
	Slots, Notches	2	S1	4.0%	S4	2.5%
	Conductor Width	2	S1	4.0%	S4	2.5%
	Conductor Spacing	2	S1	4.0%	S4	2.5%
	Misalignment of Hole and Land	2	S1	4.0%	S	2.5%
	Positional Tolerance of Hole Centres	2	S1	4.0%	S4	2.5%
	* Misalignment of Solder Resist and Land	2a	S1	4.0%	S4	2.5%
Sub-Group A3						
	Spare group for additional A tests					

Inspection Group	Characteristic	Test No	Level A		Level C	
			IL	AQL	IL	AQL
Group B						
Sub-Group B1						
	Dimensional Interchangeability					
	Board Thickness in the edge contact zone	2	-	-	S2	2.5%
	Flatness	12a	-	-	S2	2.5%
Sub-Group B2						
	Solderability					
	Unconditioned	14a	S2	2.5%	S3	2.5%
	* After Accelerated Aging	20a	-	-	S3	2.5%
Sub-Group B3						
	Thermal Shock Tests					
	Not Applicable					
Sub-Group B4						
	Mechanical Tests					
	Peel Strength	10a	-	-	S2	2.5%
	Pull-off strength of lands with plain holes	11a	-	-	S2	2.5%
Sub Group B5						
	Surface Finish Tests					
	Adhesion of Plating	#13a	S1	2.5%	S2	2.5%
	* Thickness of edge	13f	-	-	S2	2.5%
	* Edge Plating Porosity	#13d	-	-	S2	2.5%
		#13e	-	-	S2	2.5%
Sub-Group B6						
	Spare group for additional 8 tests					

Inspection Group	Characteristic	Test No	Level A		Level C	
			No of Specimens	Accept: Reject	No of Specimens	Accept: Reject
<u>Group C</u>						
<u>Sub-Group C1</u>	<u>Test Interval: 3 Months</u>					
	* Process Contamination	#	-	-	20	1:2
	* Solvent Resistance	#	-	-	6	1:2
	* Resistance to Solder	#	-	-	6	1:2

NOTES:

1. The # symbol denotes that the testing detail shall be included in the relevant Capability Detail Specification.
2. This listing may be subject to continuing review, as required by the publication of new Capability Detail Specifications.

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